

ReticleSense® Airborne Particle Sensor Quartz (APSRQ)

APSRQ

- **Improve equipment set-up and long term yields by wirelessly monitoring airborne particles in real-time.**

Quickly monitors, identifies and enables troubleshooting of airborne particles down to 0.14um within semiconductor process equipment and automated material handling systems.

- **Ideal for use in FAB scanners and steppers that read barcodes and alignment in transmission.**



Speed equipment qualification with wireless measurements.

- Collect and display particle data wirelessly using the APSRQ and Particle View™ software for real-time equipment diagnostics.
- Compare past to present as well as one tool to another with recorded particle data.
- Save time by swiftly locating contamination sources with the APSRQ data and see the effect of cleanings, adjustments and repairs in real time.

Shorten equipment maintenance cycles with reticle-like form factor.

- Detect particles in real-time without opening the tool so you don't need to expose process areas to the environment.
- APSRQ goes where reticles go to find the place where particles contaminate reticles.
- Once the location of particles is identified, tools may be selectively cleaned. Open only the dirty portion, keep the clean areas clean.

Lower equipment expenses with objective and reproducible data.

- Raise your first-pass monitor reticle success, reduce your qualification expense and increase availability with APSRQ.
- Receive early warning for impending equipment failures and optimize your preventative maintenance plans.
- Establish a baseline from known clean tool, then cycle APSRQ through a candidate tool before committing monitor reticles.

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of the ReticleSense APSRQ – The most efficient and effective wireless measurement device for airborne particles.



Save Time. Save Expense. Improve Yields.

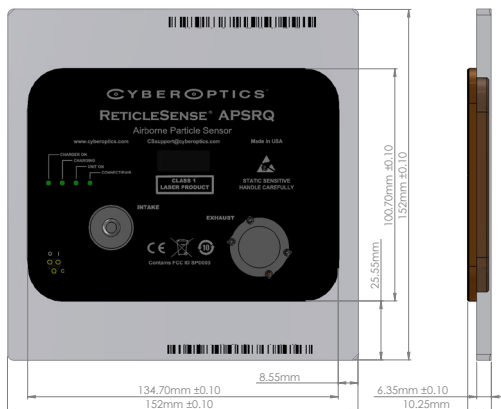
CYBEROPTICS®

Features*

Wireless, reticle-shaped and battery-powered	Available in 6 inch Reticle form factor
Easy-to-use software	ParticleView and ParticleReview software included ParticleView: Displays real-time numeric and visual feedback, cumulative or differential counting modes and density or frequency modes ParticleReview: Replays log file data for review and analysis
Highly accurate	Measures particles greater than 0.14µm Size channels: Reports particles in 0.1 µm and 0.5µm bin sizes and larger particles in 2, 5, 10 and 30 µm bin sizes.
Durable housing	Quartz outer frame: Rear surface of quartz frame is an uninterrupted quartz surface
Weight	312g (+/- 15g)
Barcodes and Alignment	Bar codes and alignment marks allow placement in most scanners and steppers
Airflow	0.07CFM (2L/min) @ 1 atmosphere
Operating pressure	0.4 to 1.6 atmosphere
Operating internal temperature	15 deg C to 45 deg C non-condensing
Battery-operation	>1 hour per charge. Inductive wireless charging and handsfree operation.
WaferSense Link	Bluetooth, Class 1, 2.4 GHz
Operating Systems	Windows 7, 8, 10, XP, Vista
Product components	Particle measurement device, charging clean case, carrying suitcase, USB communications link module and application software
Calibration	Factory recalibration recommended annually

*Specifications subject to change without notice

Dimensions



ParticleView™



Real-time data.



Contact CyberOptics today for your complimentary on-tool demonstration
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